

<b>Notice of References Cited</b>	Application/Control No. 10/506,995		Applicant(s)/Patent Under Reexamination NUN ET AL.	
	Examiner EDMUND H. LEE		Art Unit 1791	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,420,091	07-2002	Nakayama et al.	430/302
	B	US-			
	C	US-			
	D	US-			
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	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	O	JP 9-110414	04-1997	JP	-----	-----
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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